

Accelerating transient fault injection campaigns by using Dynamic HDL Slicing

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE Nordic Circuits and Systems Conference (NORCAS) : NORCHIP and International Symposium of System-on-Chip (SoC), 29-30 October 2019, Helsinki, Finland : proceedings in IEEE Xplore 2019 / 7 p. : ill <https://doi.org/10.1109/NORCHIP.2019.8906932>

Efficient fault injection based on dynamic HDL slicing technique

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 52-53 : ill <https://doi.org/10.1109/IOLTS.2019.8854419>

Enabling cross-layer reliability and functional safety assessment through ML-based compact models

Alexandrescu, Dan; **Balakrishnan, Aneesh;** Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159750>

Machine learning to tackle the challenges of transient and soft errors in complex circuits

Lange, Thomas; **Balakrishnan, Aneesh;** Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Greece 2019 / p. 7-14 : ill <https://doi.org/10.1109/IOLTS.2019.8854423>

On the estimation of complex circuits functional failure rate by machine learning techniques

Lange, Thomas; **Balakrishnan, Aneesh;** Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 49th Annual IEEE/IFIP International Conference on Dependable Systems and Networks - DSN 2019 : Supplemental Volume : proceedings 2019 / p. 35-41 : ill <https://doi.org/10.1109/DSN-S.2019.00021>